

# International IR Rectifier

- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Ease of Parallelizing
- Simple Drive Requirements
- Lead-Free

## Description

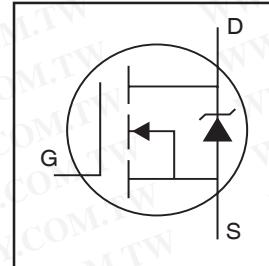
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole.

PD - 96293

# IRFP260MPbF

HEXFET® Power MOSFET



$V_{DSS} = 200V$

$R_{DS(on)} = 0.04\Omega$

$I_D = 50A$



TO-247AC

## Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	50	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	35	
$I_{DM}$	Pulsed Drain Current ①	200	
$P_D @ T_C = 25^\circ C$	Power Dissipation	300	W
	Linear Derating Factor	2.0	W/°C
$V_{GS}$	Gate-to-Source Voltage	±20	V
$E_{AS}$	Single Pulse Avalanche Energy ②	560	mJ
$I_{AR}$	Avalanche Current ①	50	A
$E_{AR}$	Repetitive Avalanche Energy ①	30	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$ ③	10	V/ns
$T_J$	Operating Junction and	-55 to +175	°C
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 seconds		
	Mounting torque, 6-32 or M3 screw	10 lbf·in (1.1 N·m)	

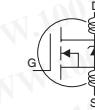
## Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{0JC}$	Junction-to-Case	—	0.50	°C/W
$R_{0CS}$	Case-to-Sink, Flat, Greased Surface	0.24	—	
$R_{0JA}$	Junction-to-Ambient	—	40	

# IRFP260MPbF

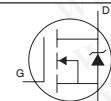
## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	200	—	—	V	$V_{\text{GS}} = 0\text{V}$ , $I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.26	—	$\text{V}^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = 1\text{mA}$
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	—	0.04	$\Omega$	$V_{\text{GS}} = 10\text{V}$ , $I_D = 28\text{A}$ ④
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{\text{DS}} = V_{\text{GS}}$ , $I_D = 250\mu\text{A}$
$g_{\text{fs}}$	Forward Transconductance	27	—	—	S	$V_{\text{DS}} = 50\text{V}$ , $I_D = 28\text{A}$ ④
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	—	—	25	$\mu\text{A}$	$V_{\text{DS}} = 200\text{V}$ , $V_{\text{GS}} = 0\text{V}$
		—	—	250		$V_{\text{DS}} = 160\text{V}$ , $V_{\text{GS}} = 0\text{V}$ , $T_J = 150^\circ\text{C}$
$I_{\text{GSS}}$	Gate-to-Source Forward Leakage	—	—	100	$\text{nA}$	$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{\text{GS}} = -20\text{V}$
$Q_g$	Total Gate Charge	—	—	234	$\text{nC}$	$I_D = 28\text{A}$
$Q_{\text{gs}}$	Gate-to-Source Charge	—	—	38		$V_{\text{DS}} = 160\text{V}$
$Q_{\text{gd}}$	Gate-to-Drain ("Miller") Charge	—	—	110		$V_{\text{GS}} = 10\text{V}$ ④
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	17	—	$\text{ns}$	$V_{\text{DD}} = 100\text{V}$
$t_r$	Rise Time	—	60	—		$I_D = 28\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	55	—		$R_G = 1.8\Omega$
$t_f$	Fall Time	—	48	—		$V_{\text{GS}} = 10\text{V}$ ④
$L_D$	Internal Drain Inductance	—	5.0	—	$\text{nH}$	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	13	—		
$C_{\text{iss}}$	Input Capacitance	—	4057	—		$V_{\text{GS}} = 0\text{V}$
$C_{\text{oss}}$	Output Capacitance	—	603	—	$\text{pF}$	$V_{\text{DS}} = 25\text{V}$
$C_{\text{rss}}$	Reverse Transfer Capacitance	—	161	—		$f = 1.0\text{MHz}$



## Source-Drain Ratings and Characteristics

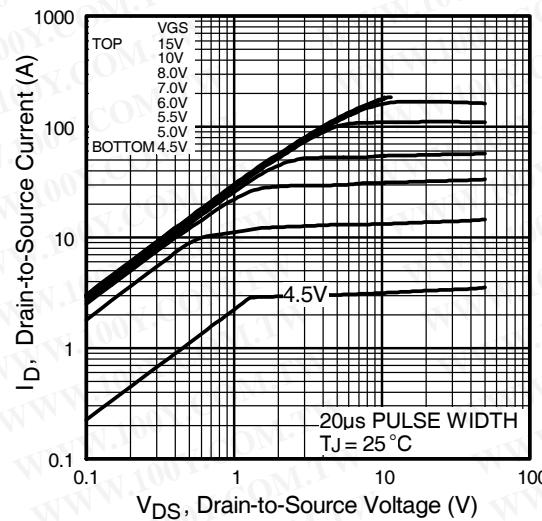
	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	50	$\text{A}$	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{\text{SM}}$	Pulsed Source Current (Body Diode) ①	—	—	200		
$V_{\text{SD}}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}$ , $I_S = 28\text{A}$ , $V_{\text{GS}} = 0\text{V}$ ④
$t_{\text{rr}}$	Reverse Recovery Time	—	268	402	ns	$T_J = 25^\circ\text{C}$ , $I_F = 28\text{A}$
$Q_{\text{rr}}$	Reverse Recovery Charge	—	1.9	2.8	$\mu\text{C}$	$dI/dt = 100\text{A}/\mu\text{s}$ ④
$t_{\text{on}}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ )				



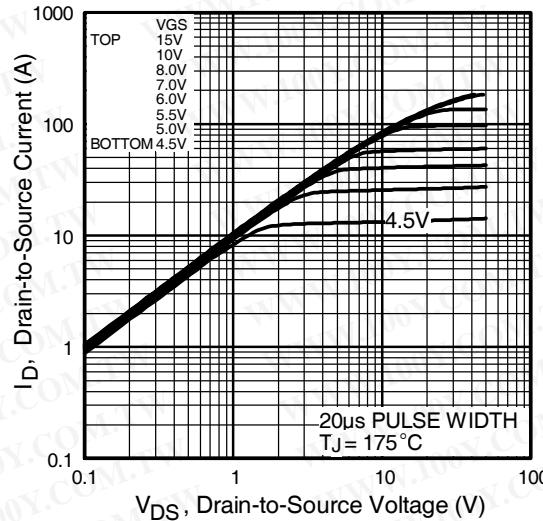
### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 1.5\text{mH}$   
 $R_G = 25\Omega$ ,  $I_{AS} = 28\text{A}$ .
- ③  $I_{SD} \leq 28\text{A}$ ,  $di/dt \leq 486\text{A}/\mu\text{s}$ ,  $V_{\text{DD}} \leq V_{(\text{BR})\text{DSS}}$ ,  $T_J \leq 175^\circ\text{C}$ .
- ④ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .

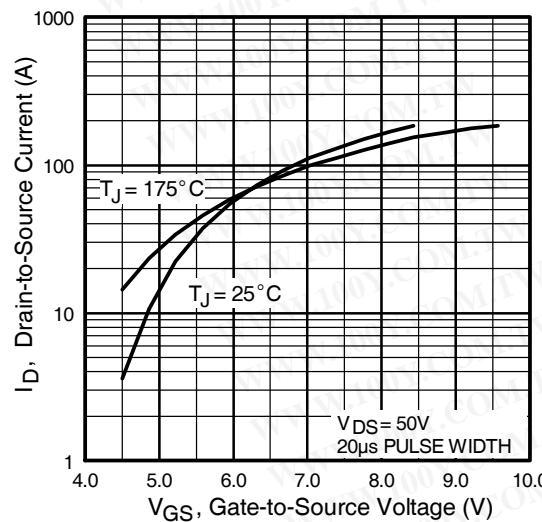
## IRFP260MPbF



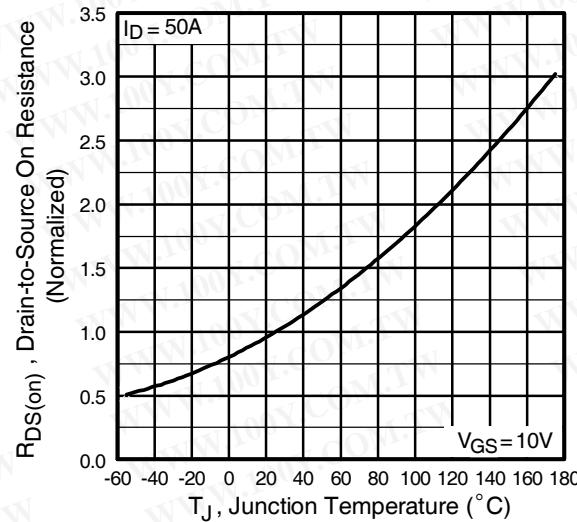
**Fig 1.** Typical Output Characteristics



**Fig 2.** Typical Output Characteristics



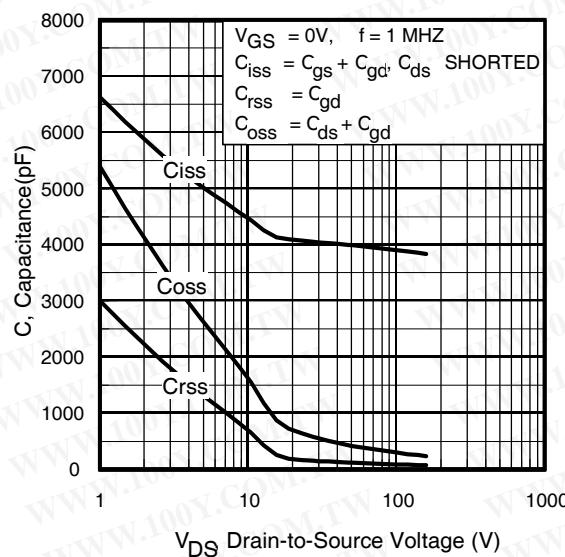
**Fig 3.** Typical Transfer Characteristics



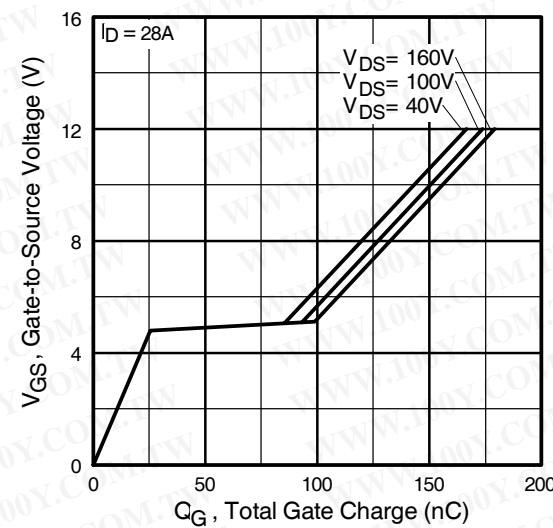
**Fig 4.** Normalized On-Resistance  
Vs. Temperature

# IRFP260MPbF

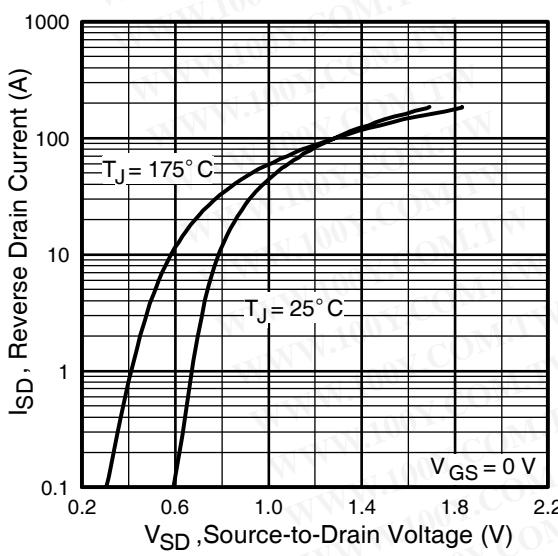
International  
ICR Rectifier



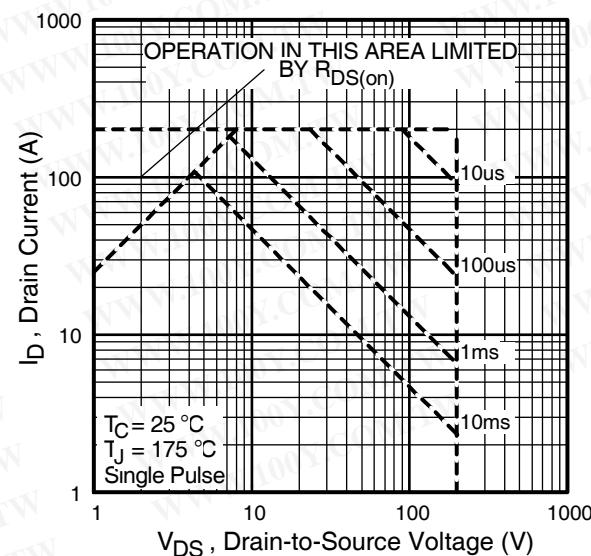
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



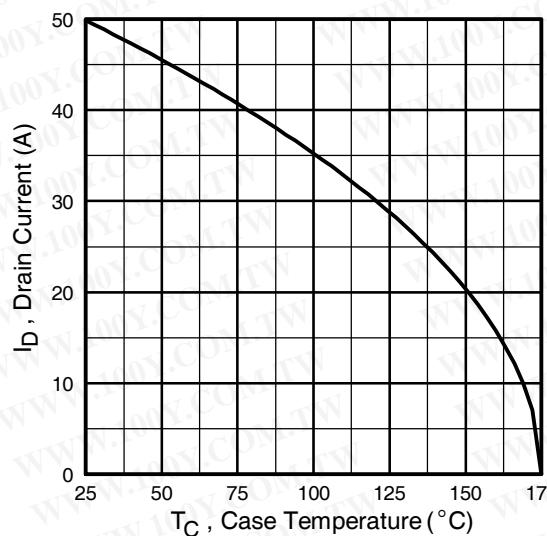
**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



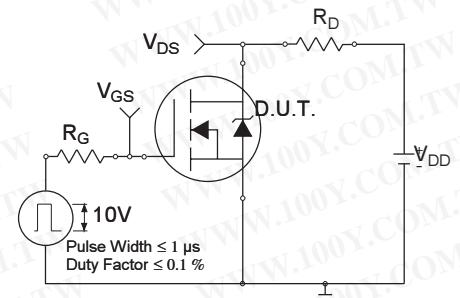
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



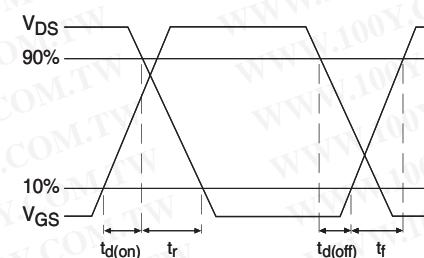
**Fig 8.** Maximum Safe Operating Area



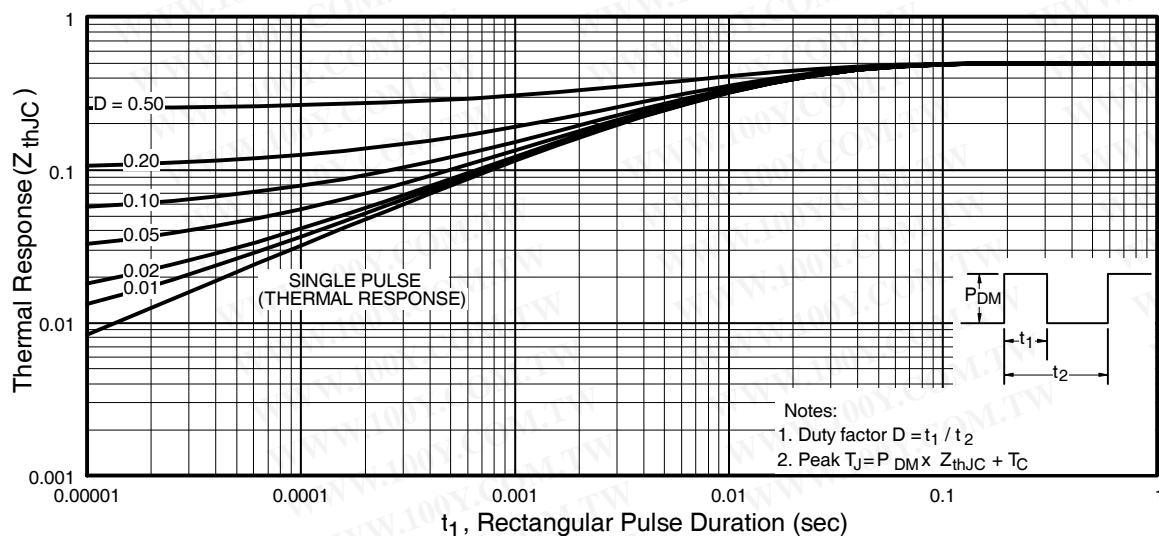
**Fig 9.** Maximum Drain Current Vs.  
Case Temperature



**Fig 10a.** Switching Time Test Circuit

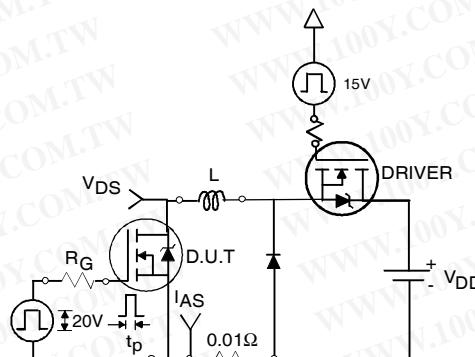


**Fig 10b.** Switching Time Waveforms

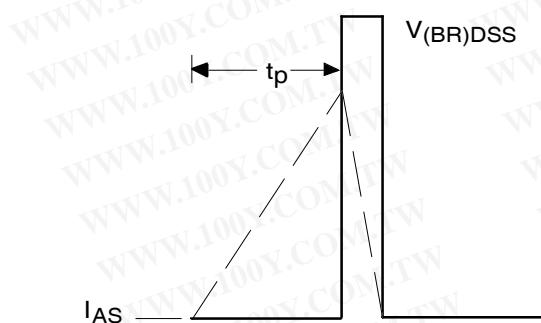


**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

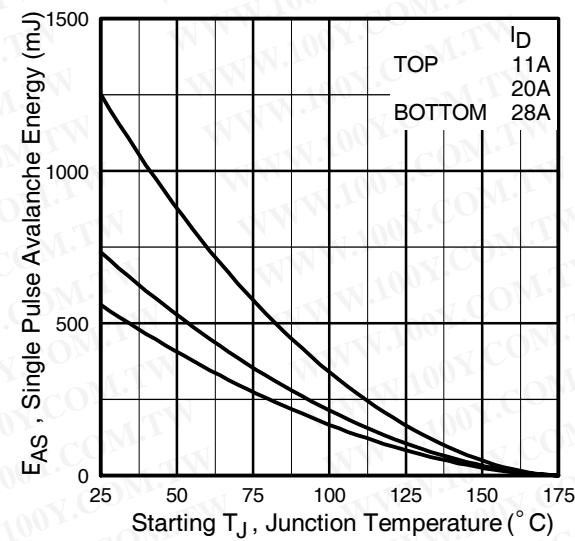
# IRFP260MPbF



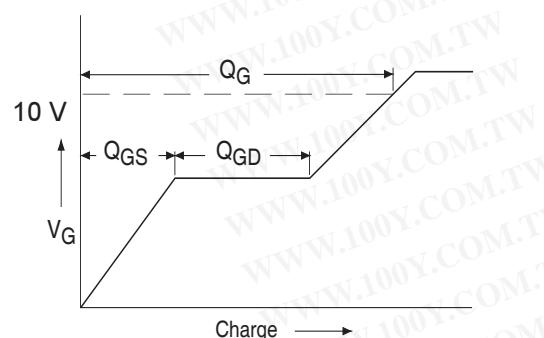
**Fig 12a.** Unclamped Inductive Test Circuit



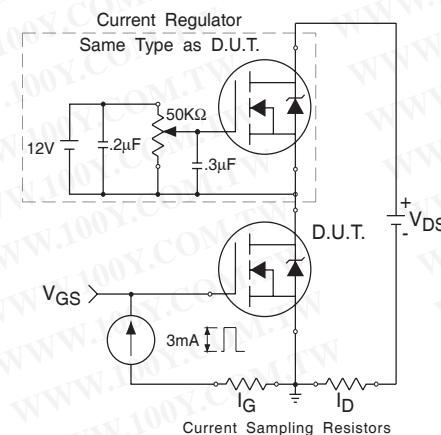
**Fig 12b.** Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current



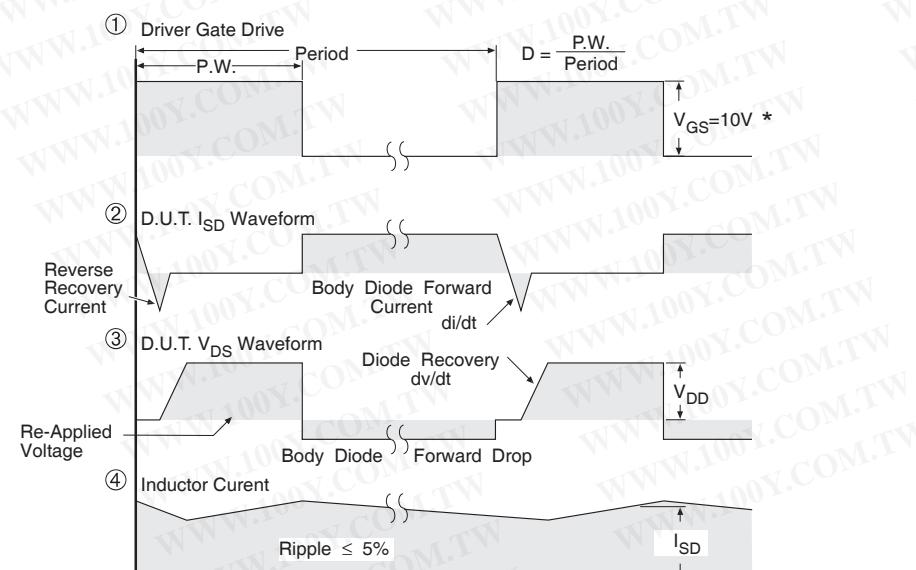
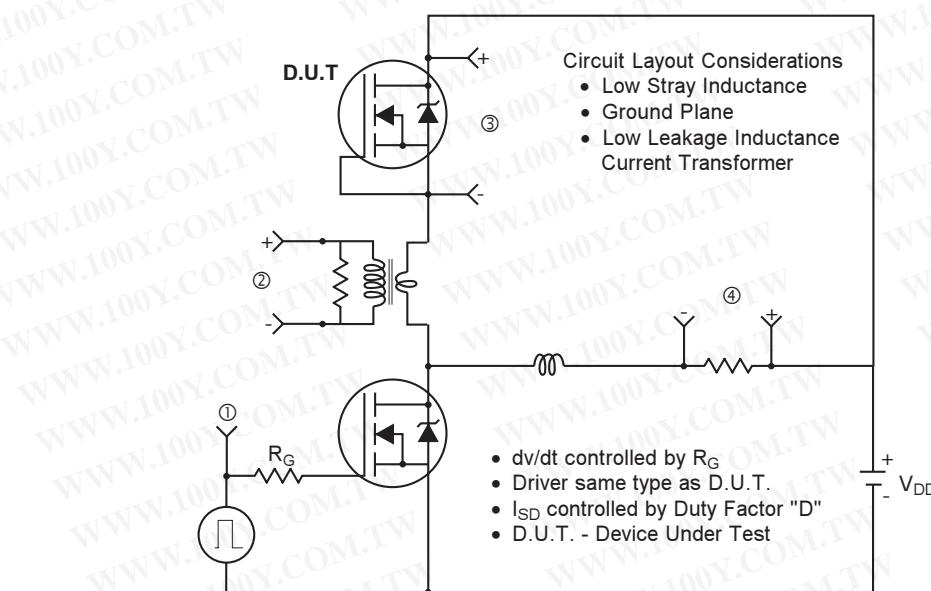
**Fig 13a.** Basic Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit

# IRFP260MPbF

## Peak Diode Recovery dv/dt Test Circuit



\*  $V_{GS} = 5V$  for Logic Level Devices

**Fig 14. For N-Channel HEXFETS**

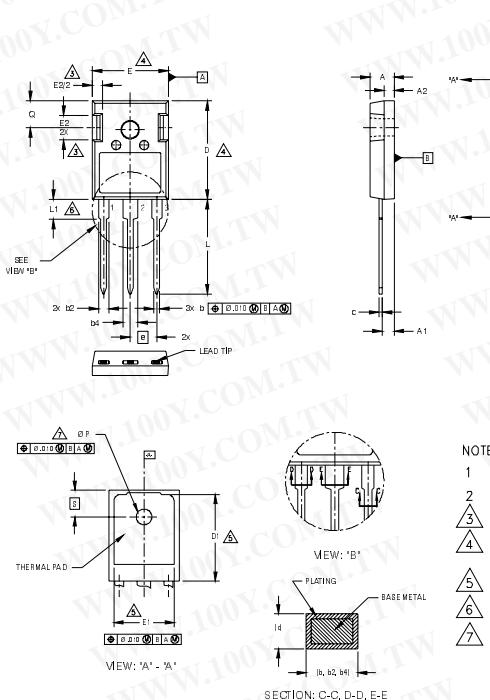
勝特力材料 886-3-5753170  
 胜特力电子(上海) 86-21-34970699  
 胜特力电子(深圳) 86-755-83298787

[Http://www.100y.com.tw](http://www.100y.com.tw)

International  
**IR** Rectifier

# IRFP260MPbF

TO-247AC Package Outline (Dimensions are shown in millimeters (inches))



SYMBOL	DIMENSIONS		NOTES
	INCHES	MILLIMETERS	
A	.190 .204	4.83 5.20	
A1	.090 .100	2.29 2.54	
A2	.075 .085	1.91 2.16	
b	.042 .052	1.07 1.33	
b2	.075 .094	1.91 2.41	
b4	.113 .133	2.87 3.38	
c	.022 .026	0.55 0.68	
D	.819 .830	20.80 21.10	4
D1	.640 .694	16.25 17.65	5
E	.620 .635	15.75 16.13	
E1	.512 .570	13.00 14.50	4
E2	.145 .196	3.68 5.00	
e	.215 Typical	5.45 Typical	
L	.780 .800	19.80 20.32	
L1	.161 .173	4.10 4.40	
Ø P	.138 .143	3.51 3.65	
Q	.216 .236	5.49 6.00	
S	.238 .248	6.04 6.30	

#### LEAD ASSIGNMENTS

##### HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

##### IGBTs, CoPACK

- 1.- GATE
- 2.- COLLECTOR
- 3.- Emitter
- 4.- COLLECTOR

##### DIODES

- 1.- ANODE/OPEN
- 2.- CATHODE
- 3.- ANODE

#### NOTES:

- 1 DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M 1994.
- 2 DIMENSIONS ARE SHOWN IN INCHES AND MILLIMETERS.
- 3 CONTOUR OF SLOT OPTIONAL.
- 4 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5 THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS D1 & E1.
- 6 LEAD FINISH UNCONTROLLED IN L1.
- 7 Ø P TO HAVE A MAXIMUM DRAFT ANGLE OF 1.5 ° TO THE TOP OF THE PART WITH A MAXIMUM HOLE DIAMETER OF .154 INCH.

## TO-247AC Part Marking Information

EXAMPLE: THIS IS AN IRFPE30  
 WITH ASSEMBLY  
 LOT CODE 5657  
 ASSEMBLED ON WW 35, 2001  
 IN THE ASSEMBLY LINE 'H'

Note: 'P' in assembly line position  
 indicates 'Lead-Free'

